# Advanced Search

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# **Advanced Search**

# Background:

Sources are used insufficiently

## Goal:

Evaluation of options Roadmap towards solution

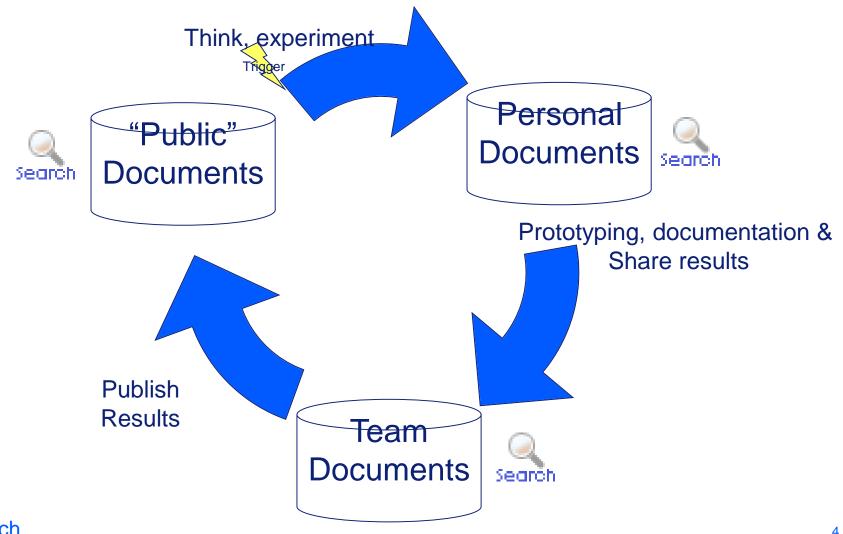
'Advanced Search' may be more about filtering irrelevant information than about adding more to the existing information overload.

## End-user brainstorm sessions 2000 / 2003

- Professional support for instruction and source knowledge
- ❖ No time to 'try' new sources
- ❖ No interest in electronic journals with so many interfaces
- Inspec doesn't cover our subject (materials, chemistry)
- One user-friendly interface for searching/collecting
- Intelligent system that 'knows' what you want
- Search engine for idiots
- Community building

Researchers don't want to search -- they want to do research.

# Research: search, documentation, collaboration and publishing



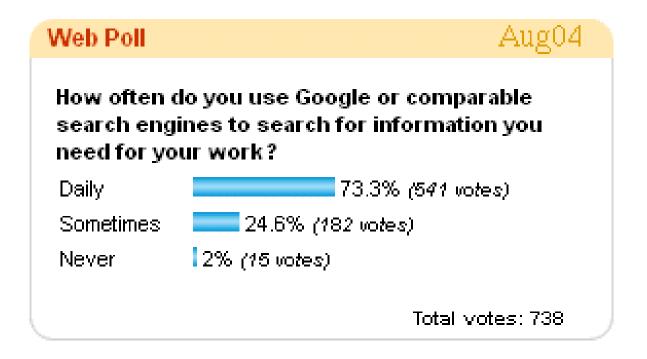
# **Vision**

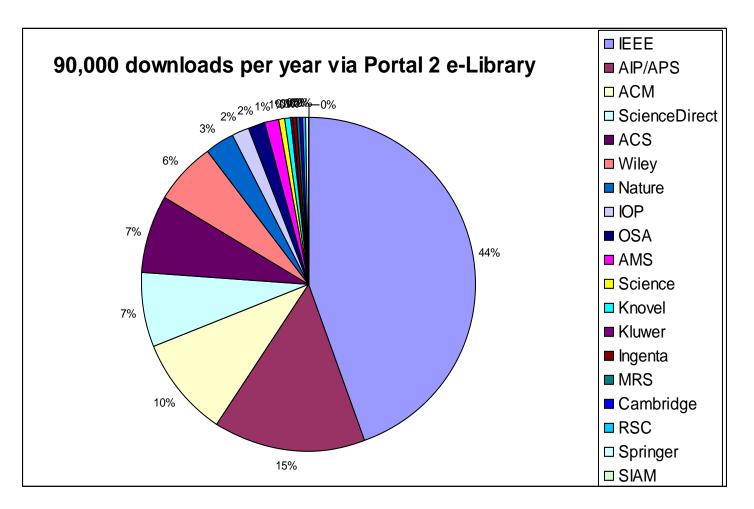
Ultimately, Advanced Search has a single point of contact for all content sources.

It provides the Research community with true and relevant information, it supports alerting and is closely integrated with document/content management.

It is a logical part of an 'e-4everything portal' that is, personalized, secure, intuitive, adaptive, always available source of information.

## **User behaviour**





.... too many interfaces....

# First steps (iterative approach)

Integration of search, collaborative content/document production and support for publication (Project workspace)

A search solution that integrates external scientific sources (Portal2 e-Library)

A taxonomy based publishing and search solution for available services and goods; rules and regulations; Campus and Company information (demand management solution)

## **Products**

- Expansion of scope of literature database Inspec: pilot in 2<sup>nd</sup> half of 2004
  - Inspec + Web of Science
  - Inspec + Scopus
- One 'portal interface' to information that can be accessed only via search interfaces: pilot in 2<sup>nd</sup> half of 2004 of:
  - > IPS (~ IEEE)
  - Endeavour (~ Elsevier)

